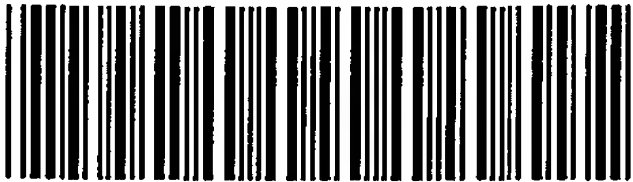


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/665,654	CHEN ET AL.	
	Examiner	Art Unit	
	Linh M. Nguyen	2816	

SEARCHED			
Class	Subclass	Date	Examiner
327	261	06/28/05	LMN
"	263	"	"
"	264	"	"
"	268	"	"
"	288	"	"
"	290	"	"

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR